

MOS INTEGRATED CIRCUIT μ PD16315

1/4- to 1/12-DUTY FIP[™](VFD) CONTROLLER/DRIVER

DESCRIPTION

The μ PD16315 is a FIP (Fluorescent Indicator Panel, or Vacuum Fluorescent Display) controller/driver that is driven on a 1/4- to 1/12- duty factor. It consists of 16 segment output lines, 4 grid output lines, 8 segment/grid output drive lines, a display memory, a control circuit, and a key scan circuit. Serial data is input to the μ PD16315 through a three-line serial interface. This FIP controller/driver is ideal as a peripheral device for a single-chip microcomputer.

FEATURES

- Multiple display modes: 16-segment & 12-digit to 24-segment & 4-digit
- Key scanning: 16 x 2 matrix
- Dimming circuit: 8 steps
- High-withstanding-voltage output: VDD 35 V MAX.
- LED ports: 4 chs., 20 mA MAX.
- No external resistors necessary for driver outputs: P-ch open-drain + pull-down resistor output
- Serial interface: CLK, STB, DIN, DOUT

ORDERING INFORMATION

Part Number Package

 μ PD16315GB-3BS

44-pin Plastic QFP (10 x 10)

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1. BLOCK DIAGRAM



2. PIN CONFIGURATION (Top View)

44-pin Plastic QFP (10 x 10)



Caution Use all of the power supply pins.

3. PIN FUNCTION

Symbol	Pin Name	Pin No.	I/O	Description
Din	Data input	7	Input	Input serial data at rising edge of shift clock, starting from the low order bit.
Dout	Data output	6	Output	Output serial data at the falling edge of the shift clock, starting from low order bit. This is N-ch open-drain output pin.
STB	Strobe	9	_	Initializes serial interface at the rising or falling edge of the μ PD16315. It then waits for reception of a command. Data input after STB has fallen is processed as a command. While command data is processed, current processing is stopped, and the serial interface is initialized. While STB is high, CLK is ignored.
CLK	Clock input	8	Input	Reads serial data at the rising edge, and outputs data at the falling edge.
OSC	Oscillator pin	5	_	Connect resistor to this pin to determine the oscillation frequency to this pin. Connect resistor between this pin and GND (Vss).
Seg1/KS1 to Seg16/KS16	High-withstanding-voltage output (Segment)	14 to 29	Output	Segment output pins (Dual function as key source)
Grid1 to Grid4	High-withstanding-voltage output (grid)	39 to 42	Output	Grid output pins
Seg17/Grid12 to Seg24/Grid5	High-withstanding-voltage output (segment/grid)	31 to 38	Output	These pins are selectable for segment or grid driving.
LED1 to LED4	LED output	1 to 4	Output	CMOS output, +20 mA MAX.
KEY ₁ , KEY ₂	Key data input	10, 11	Input	Data input to these pins is latched at the end of the display cycle.
Vdd	Logic power	13, 43	-	5 V ± 10%
Vss	Logic ground	12, 44	-	Connect this pin to system GND.
VEE	Pull-down level	30	_	Vdd – 35 V MAX.

4. DISPLAY RAM ADDRESS AND DISPLAY MODE

The display RAM stores the data transmitted to the μ PD16315 through the serial communication. The addresses are allocated in 8-bit units.

Seg1 Seg4	Seg ₈	Seg	2 Seg16	6 Seg ₂₀	Seg ₂₄	_
00H∟	00H u	01H∟	01H∪	02H∟	02H ∪	DIG ₁
03H∟	03H υ	04H∟	04H ∪	05H∟	05H ∪	DIG ₂
06H∟	06H u	07H∟	07H ∪	08H∟	08H ∪	DIG₃
09H∟	09H u	0AH∟	0AHu	0BH∟	0BHu	DIG4
0CH⊾	0CH⊍	0DH∟	0DHu	0EH∟	0EHu	DIG₅
0FH∟	0FHu	10H∟	10H∪	11H∟	11H∪	DIG ₆
12H∟	12Hu	13H∟	13H ∪	14H∟	14H ∪	DIG7
15H∟	15Η υ	16H∟	16H∪	17H∟	17H∪	DIGଃ
18H∟	18Η υ	19H∟	19H ∪	1AH∟	1AH∪	DIG9
1BH∟	1BHu	1CH∟	1CH⊍	1DH∟	1DHu	DIG ₁₀
1EH∟	1EHu	1FH∟	1FH∪	20H∟	20H u	DIG11
21H∟	21H υ	22H∟	22H ⊍	23H∟	23H u	DIG ₁₂

<u>b0</u>	b3	b4 b7
	XXH∟	XXHυ
	Lower 4 bits	Higher 4 bits

5. KEY MATRIX AND KEY-INPUT DATA STORAGE RAM



The key matrix is made up of a 16 x 2 matrix, as shown below.

The data of each key is stored as follows, and is read with the read command starting from the least significant bit.

KEY1	KEY ₂	KEY ₁	KEY ₂	KEY1	KEY ₂	KEY1	KEY ₂	_	
Seg	1/KS1	Seg	2/KS2	Sega	ø/KS₃	Seg	4/KS4		
Seg	5/KS5	Sege	/KS6	Seg	/KS7	Seg	8/KS8		
Seg	9/KS9	Seg	/KS10	Seg	/KS11	Seg₁	2/KS12		Reading Sequence
Seg	3/KS13	Seg ₁₄	/KS14	Seg	5/KS15	Seg	6/KS16	V	,
b0	b1	b2	b3	b4	b5	b6	b7		

5.1 LED Port

Data is written to the LED port with the write command, starting from the least significant bit. "L" output when the bit of this port is 0, and "H" output when the bit is 1. The data of bits after the 5th bit are ignored.



Remark Power ON application, all the LED ports are "L" output.

6. COMMANDS

Commands set the display mode and status of the $FIP^{TM}(VFD)$ driver.

The first 1 byte input to the μ PD16315 through the D_{IN} pin after the STB pin has fallen is regarded as a command. If STB is set high while commands/data are transmitted, serial communication is initialized, and the commands/data being transmitted are invalid (however, the commands/data previously transmitted remain valid).

(1) Display mode setting commands

These commands initialize the μ PD16315 and select the number of segments and the number of grids (1/4- to 1/12duty, 16 segments to 24 segments).

When these commands are executed, the display is forcibly turned OFF, and key scanning is also stopped. To resume display, the display command "ON" must be executed. If the same mode is selected, however, nothing happens.



Remark Power ON application, the 12-digit, 16-segment mode is selected.

(2) Data setting commands

These commands set data write and data read modes.





(3) Address setting commands

These commands set an address of the display memory.



- **Remarks 1.** If address 24H or higher is set, data is ignored, until a valid address is set.
 - 2. Power ON application, the address is set to 00H.

(4) Display control commands



Note Power ON application, key scanning is stopped.

Remark Power ON application, the 1/16 pulse width is set and the display is turned OFF.

7. KEY SCANNING AND DISPLAY TIMING



Remark One cycle of key scanning consists of two frame, and data in a 16 x 2 matrix is stored in RAM.

Key Scan Expansion

1st frame	DIGn	1	2	3	4	5	6	7	8	DIO
2nd frame	DIGN	9	10	11	12	13	14	15	16	DIG1

8. SERIAL COMMUNICATION FORMAT

Reception (command/data write)



Transmission (data read)



- **Note** When data is read, a wait time twart of 1 μ s is necessary since the rising of the eighth clock that has set the command, until the falling of the first clock that has read the data.
- **Remark** Because the Dout pin is an N-ch, open-drain output pin, be sure to connect an external pull-up resistor (1 to 10 k Ω) to this pin.

9. ELECTRICAL SPECIFICATIONS

Parameter	Symbol	Ratings	Unit
Logic Supply Voltage	Vdd	-0.5 to +6.0	V
Driver Supply Voltage	VEE	Vdd + 0.5 to Vdd – 40	V
Logic Input Voltage	VI1	−0.5 to V _{DD} + 0.5	V
FIP Driver Output Voltage	V ₀₂	VEE - 0.5 to VDD + 0.5	V
LED Driver Output Current	lo1	±20	mA
FIP Driver Output Current	I O2	-40 (grid)	mA
		-15 (segment)	
Power Dissipation	PD	800 ^{Note}	mW
Operating Ambient Temperature	TA	-40 to +85	°C
Storage Temperature	Tstg	-65 to +150	°C

Absolute Maximum Ratings (T_A = 25°C, Vss = 0 V)

Note Derate at $-6.4 \text{ mW/}^{\circ}\text{C}$ at $T_{\text{A}} = 25^{\circ}\text{C}$ or higher.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Recommended Operating Range ($T_A = -20$ to 70°C, Vss = 0 V)

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Logic Supply Voltage	VDD	4.5	5	5.5	V
High-Level Input Voltage	VIH	0.7 Vdd		Vdd	V
Low-Level Input Voltage	VIL	0		0.3 Vdd	V
Driver Supply Votlage	VEE	0		Vdd - 35	V

Remark Maximum power consumption PMAX. = FIP driver dissipation + RL dissipation + LED driver dissipation

+ dynamic power consumption

Where segment current = 3 mA, grid current = 15 mA, and LED current = 20 mA,

FIP driver dissipation = number of segments x 6 + number of grids/(number of grids + 1) x 30 (mW)

RL dissipation $\cong (V_{DD} - V_{EE})^2/50 \text{ x} \text{ (number of segments + 1) (mW)}$

LED driver dissipation = number of LEDs x 20 (mW)

Dynamic power consumption = VDD x 5 (mW)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
High-Level Output Voltage	Vон1	LED1 - LED4, Iон1 = -15 mA	V _{DD} – 1			V
Low-Level Output Voltage	Vol1	LED1 - LED4, IOL1 = +15 mA			1	V
Low-Level Output Voltage	Vol2	Dout, Iol2 = 4 mA			0.4	V
High-Level Output Current	Іон21	$V_0 = V_{DD} - 2 V$,	-3			mA
		Seg1/ KS1 to Seg16/ KS16				
High-Level Output Current	Іон22	$V_0 = V_{DD} - 2 V$, Grid ₁ to Grid ₄	-15			mA
		Seg17/ Grid12 to Seg24/ Grid5				
Driver Leakage Current	IOLEAK	Vo = VDD – 35 V, driver OFF			-10	μA
Output Pull-Down Resistor	R∟	Driver output	40	65	120	kΩ
Input Current	h	VI = VDD or Vss			±1	μA
High-Level Input Voltage	VIH		0.7 Vdd			V
Low-Level Input Voltage	VIL				0.3 Vdd	V
Hysteresis Voltage	Vн	CLK, DIN, STB		0.35		V
Dynamic Current Consumption	IDDdyn	Under no load, display OFF			5	mA

Electrical Characteristics (T_A = -20 to +70°C, V_{DD} = 4.5 to 5.5 V, V_{SS} = 0 V, V_{EE} = V_{DD} - 35 V)

Switching Characteristics (TA = -20 to +70°C, VDD = 4.5 to 5.5 V, VEE = -30 V)

Parameter	Symbol	Te	MIN.	TYP.	MAX.	Unit	
Oscillation Frequency	fosc	R = 82 kΩ		350	500	650	kHz
Propagation Delay Time	t PLZ	$CLK\toDout$				300	ns
	t PZL	C∟ = 15 pF, F	CL = 15 pF, RL = 10 kΩ			100	ns
Rise Time	t _{TZH1}	C∟ = 300 pF	Seg1/KS1 to Seg16/KS16			2	μs
	tTZH2		Grid₁ to Grid₄,			0.5	μs
			Seg17/Grid12 to				
			Seg ₂₄ /Grid ₅				
Fall Time	tтнz	C∟ = 300 pF, Segո, Gridn				160	μs
Maximum Clock Frequency	f мах.	Duty = 50%		1			MHz
Input Capacitance	Cı					15	pF

g Conditions (T _A = -20 to 70°C, V _{DD} = 4.5 to 5.5 V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Clock Pulse Width	PWclk		400			ns
Strobe Pulse Width	РWsтв		1			μs
Data Setup Time	t SETUP		100			ns
Data Hold Time	t HOLD		100			ns
Clock-Strobe Time	tclk-stb	$CLK \uparrow \rightarrow STB \uparrow$	1			μs
Wait Time	t wait	$CLK \uparrow \to CLK \downarrow^{Note}$	1			μs

Note Refer to the SERIAL COMMUNICATION FORMAT.

Switching Characteristic Waveforms



10. APPLICATIONS



Updating display memory by incrementing address

Data : display data

11. CIRCUIT EXAMPLE FOR APPLICATION



12. PACKAGE DRAWING

44-PIN PLASTIC QFP (10x10)



NOTE

Each lead centerline is located within 0.16 mm of its true position (T.P.) at maximum material condition.

ITEM MILLIMETERS 13.2±0.2 А В 10.0±0.2 С 10.0±0.2 13.2±0.2 D F 1.0 G 1.0 $0.37\substack{+0.08\\-0.07}$ н 0.16 T J 0.8 (T.P.) κ 1.6±0.2 L 0.8±0.2 $0.17^{+0.06}_{-0.05}$ М Ν 0.10 2.7±0.1 Р 0.125±0.075 Q $3^{\circ}^{+7^{\circ}}_{-3^{\circ}}$ R S 3.0 MAX. S44GB-80-3BS-2

detail of lead end

S

13. RECOMMENDED SOLDERING CONDITIONS

The following conditions must be met for soldering conditions of the μ PD16315.

For more details, refer to the Semiconductor Device Mounting Technology Manual (C10535E).

Please consult with our sales offices in case other soldering process is used, or in case the soldering is done under different conditions.

Type of Surface Mount Device

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak package's surface temperature: 235°C or below,	IR35-00-3
	Reflow time: 30 seconds or below (210°C or higher),	
	Number of reflow process: MAX.3	
VPS	Peak package's temperature: 215°C or below,	VP15-00-3
	Reflow time: 25 to 40 seconds (200°C or higher),	
	Number of reflow process: MAX.3	
Wave Soldering	Solder temperature: 260°C or below,	WS60-00-1
	Flow time: 10 seconds or below	
	Temperature of pre-heat: 120°C pr below (Plastic surface	
	temperature)	
	Number of flow process: 1	
Partial heating method	Terminal temperature: 300°C or below,	_
	Time 3 seconds or below (per side of pin position)	

<u>µ PD16315GB-3BS : 44-pin plastic QFP (10 x 10)</u>

Caution Do not apply more than a single process at once, except for partial heating method.

- NOTES FOR CMOS DEVICES -

① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

(2) HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Reference Documents

NEC Semiconductor Device Reliability/Quality Control System (C10983E)

Quality Grades On NEC Semiconductor Devices (C11531E)

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